

Application of Surface Physics for Instruments in Space Science

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Abstract

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List of Acronyms

BCVD Boron-doped Chemical Vapour Deposition

DLC Diamond-Like Carbon surface

EMG Exponentially Modified Gaussian

ENA Energetic Neutral Atoms

FWHM Full Width at Half Maximum

IBEX Interstellar Boundary EXplorer

ILENA Imager for Low Energetic Neutral Atoms

IMAP Interstellar Mapping and Acceleration Probe

JVIA Jovian Neutral Atom Analyser

JUICE JUpiter ICy moon Explorer

L1 Lagrange 1

LISM Local InterStellar Medium

MCA MultiChannel Analyzer

MCP MultiChannel Plate

PA PostAcceleration voltage

PEP Particle Environment Package

RPA Retarding Potential Analyser

1 Introduction

JUICE PEP NIM

2 Theory

2.1 Requirements

2.2 Basic Theory about a TOF instrument

A time of flight mass spectrometer consists of, an ion-source, a mass analyser and a detector.

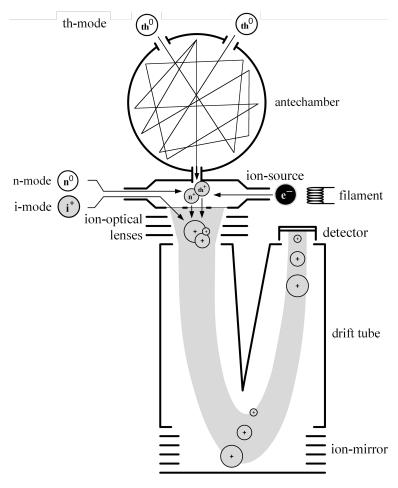


Figure 1: Schematics of the NIM mass spectrometer. Adapted from [2].

In the ion-source, the ions are formed. The NIM instrument is able to measure neutrals and ions. Ions entering the source are let directly to the mass analyser. Neutral particles get ionised with and electron emitting filament. The formed ions get accelerated to the same energy and fly through the spectrometer. Light particles fly faster through the spectrometer than heavier ones. The different particle species arrive at different times at the detector. The used detector is an MCP detector. To enhance the flight distance without enlarge the instrument, an ion-mirror is used.

2.2.1 Ion-source

To calculate the number of ions produced in the ion source we use:

$$I_{ion} = \beta \cdot Q_{ion} \cdot L \cdot n \cdot I_{em} \tag{1}$$

With β the extraction efficiency which is 1, L as the effective ionising path in our case 4 mm, n the particle density, I_{em} the electron emission current from the filament and Q_{ion} the ionising cross section. The cross sections of species used in our calibration can be found in table

3 Setup

- 3.1 NIM Instrument
- 3.1.1 Prototype
- 3.1.2 Protoflight Model
- 3.2 Test facilities/ Test Tools

4 Experiments

In this section, the different tests are described to develop the NIM instrument. All measurements were performed in the STROFIO vacuum chamber.

4.1 Reflectron

The NIM prototype reflectron was exchanged through the flight like reflectron, which was tested. The NIM prototype reflectron consisted of 12 ring electrodes connected with each other with resistors in between them. On the first, 5th and 12th electrode, a voltage can be applied. With the different resistors, a linear voltage gradient in the reflectron is generated. The flight reflectron consists of a ceramic tube with two resistance spirals on its inner walls. There are three electrodes, where the voltage can be applied. The electrodes are connected via resistance spirals with each other. The two reflectrons can be seen in Fig. 2. This kind of reflectron was also used in the RTOF mass spectrometer which flied in ROSINA [3] and the in the NGMS [1].

Therefore, the two reflectrons are from the electrical point of view the same.



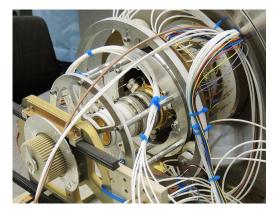


Figure 2: Left: Prototype reflectron with ringelectrodes. Right: Flight reflectron

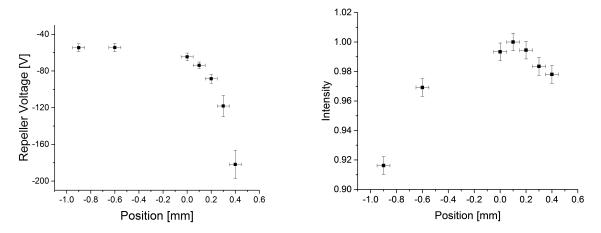


Figure 3: Left: The filament repeller voltage to reach the maximum electron intensity over the volume of the neutral particles. Right: Electron intensity normed on the intensity at position 0.

4.1.1 Measurement Principle

4.1.2 Discussion

4.2 CASYMIR-D/-E

4.3 Simulations

4.4 Pulser

4.5 Detector Tests

4.6 Ionoptics

5 Conclusion

6 Outlook

References

- [1] L. Hofer. Development of the gas chromatograph mass spectrometer to investigate volatile species in the lunar soil for the Luna-Resurs mission. Universität Bern, 2015.
- [2] S. Meyer. <u>Development of a Neutral Gas-and Ion-Mass Spectrometer for Jupiter's Moons</u>. Universität Bern, 2017.
- [3] S. Scherer. Design of a high-performance Reflect:ron Time-of-Flight mass spectrometer for space applications. Universität Bern, 1999.

7 Appendix

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<u>Erklärung</u>

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